

“Atom column detection from simultaneously acquired ABF and ADF STEM images”.
Fatermans J, den Dekker Aj, Müller-Caspary K, Gauquelin N, Verbeeck J, Van Aert S,
Ultramicroscopy **219**, 113046 (2020). <http://doi.org/10.1016/j.ultramic.2020.113046>